

## **N-Channel Enhancement MOSFET**

#### **Features**

- Drain-Source Breakdown Voltage V<sub>DSS</sub> 30 V
- Drain-Source On-Resistance  $R_{DS(ON)}\,8.5m\Omega, \text{ at V}_{GS} = 10\text{V}, \text{ I}_{DS} = 5.5\text{A}$   $R_{DS(ON)}\,12m\Omega, \text{ at V}_{GS} = 4.5\text{V}, \text{ I}_{DS} = 5.5\text{A}$
- Continuous Drain Current at T<sub>C</sub>=25°C I<sub>D</sub> = 11A
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

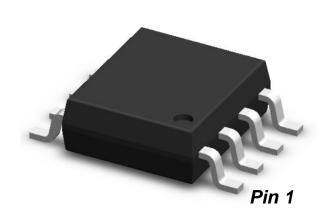
## **Applications**

- Power Management
- Lithium Ion Battery

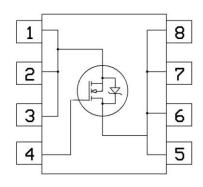
## **Description**

The CTL1103NS uses high performance Trench Technology to provide excellent  $R_{\text{DS(ON)}}$  and low gate charge which is suitable for most of the synchronous buck converter applications .

## **Package Outline**



## **Schematic**



Source: 1, 2, 3

Gate: 4

Drain: 5, 6, 7, 8



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## Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
V <sub>DS</sub>	Drain-Source Voltage	30	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current	11	А	1
I <sub>DM</sub>	Pulsed Drain Current	40	А	1
$P_D$	Total Power Dissipation	1.6	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
$T_J$	Operating Junction Temperature Range	-55 to 150	°C	

## **Thermal Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
В	Thermal Resistance			C.F.		00 444	4.4
$R_{\Theta JA}$	Junction-Ambient (t=10s)		-	65	-	°C W	1,4



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# Electrical Characteristics Tc = 25°C (unless otherwise specified)

#### **Static Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
B <sub>VDSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250 $\mu$ A	30	-	-	V	
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS} = 30V$ , $V_{GS} = 0V$	-	-	1	μΑ	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 20V$ , $V_{DS} = 0V$	-	-	±100	nA	

#### **On Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Мах	Units	Notes
D	Drain Course On Decistores	V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.5A	-	8.5	10	mΩ	Fig
R <sub>DS(ON)</sub>	Drain-Source On-Resistance	$V_{GS} = 4.5V, I_D = 5.5A$	-	12	17	mΩ	5
V <sub>GS(TH)</sub>	Gate-Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \muA$	1	-	3	V	Fig 8

## **Dynamic Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
Ciss	Input Capacitance	V <sub>DS</sub> = 10V ,	-	1390	-		
Coss	Output Capacitance	$V_{GS} = 0V$ ,	-	152	-	pF	Fig 7
Crss	Reverse Transfer Capacitance	f=1Mhz	-	217	-		

## **Switching Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
T <sub>D(ON)</sub>	Turn-On Delay Time	\/ 45\/ \/ 40\/	-	7.5	-		
T <sub>R</sub>	Rise Time	$V_{DS} = 15V$ , $V_{GS} = 10V$ , $R_{L} = 2.73\Omega$ $R_{G} = 4.7\Omega$	-	42	-		Fig
T <sub>D(OFF)</sub>	Turn-Off Delay Time	$R_L = 2.73\Omega R_G = 4.7\Omega$ $I_D = 5.5A$	-	33.7	-	ns	11 & 12
T <sub>F</sub>	Fall Time	ID = 3.3A	-	11.5			
Q <sub>G</sub>	Total Gate Charge	$V_{DS} = 24V$ ,	-	29	-		Fig.
Q <sub>G</sub> s	Gate-Source Charge	$V_{GS} = 10V$ ,	-	4.9	-	nC	Fig 9 & 10
Q <sub>GD</sub>	Gate-Drain (Miller) Charge	I <sub>D</sub> =11A	-	7.5	-	]	9 & 10



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#### **Drain-Source Diode Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Мах	Units	Notes
V <sub>DS</sub>	Drain-Source Forward Voltage	$V_{GS} = 0V, I_D = 11A$			-1.2	V	
Is	Continuous Forward Current				11	Α	1

#### Note:

- 1. The power dissipation is limited by 150  $^{\circ}\text{C}$  junction temperature.
- 2. Device mounted on a glass-epoxy board



FR-4

 $25.4 \times 25.4 \text{ mm}$ .

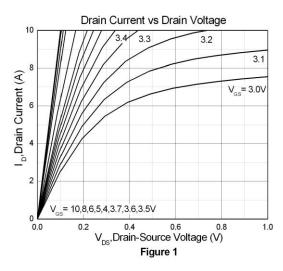
2 Oz Copper

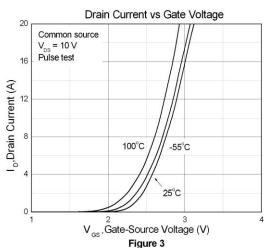
**Actual Size** 

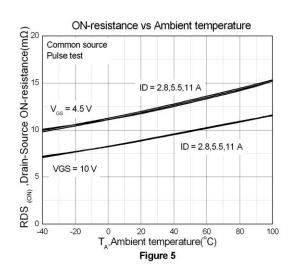
- 3. The data tested by pulsed , pulse width  $\,\leq\,300\mu s$  , duty cycle  $\,\leq\,2\%$
- 4. Thermal Resistance follow JESD51-3.

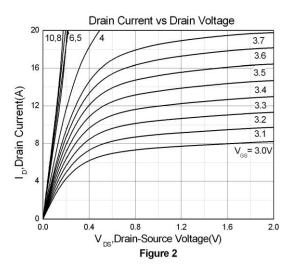


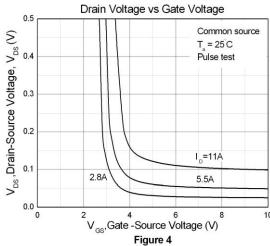
# **Typical Characteristic Curves**

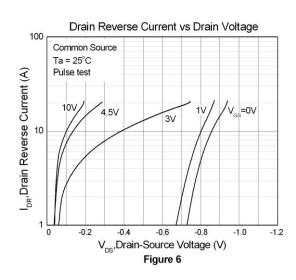






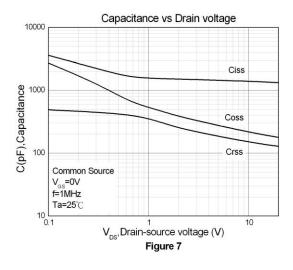


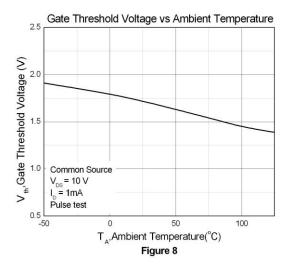






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### **Test Circuits & Waveforms**

**Figure 9: Gate Charge Test Circuit** 

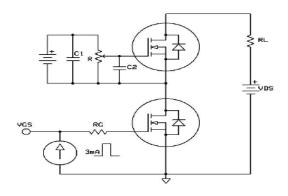
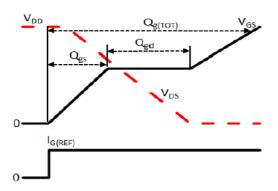
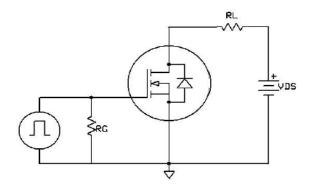


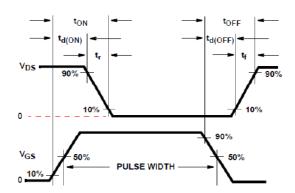
Figure 10: Gate Charge Waveform



**Figure 11: Switching Time Test Circuit** 



**Figure 12: Switching Time Waveform** 

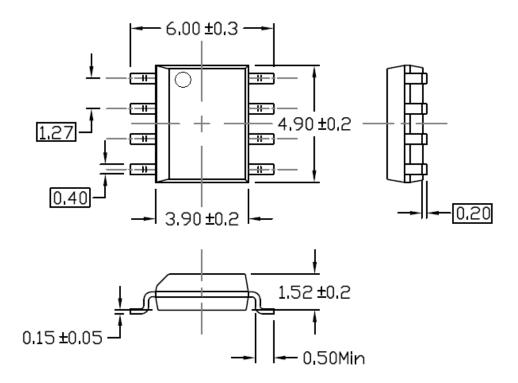


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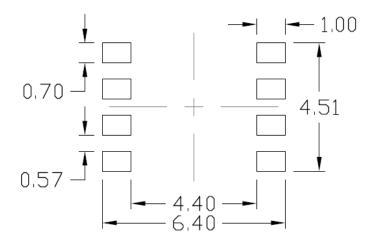


## Package Dimension Dimensions in mm unless otherwise stated



Note: Dimensions in mm

# Recommended pad layout for surface mount leadform

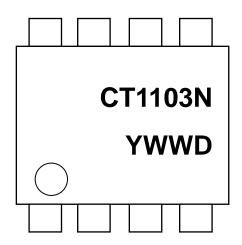


Note: Dimensions in mm



# CTL1103NS N-Channel Enhancement MOSFET

# **Marking Information**



1103N : Device Number Y : Fiscal Year

WW : Work Week

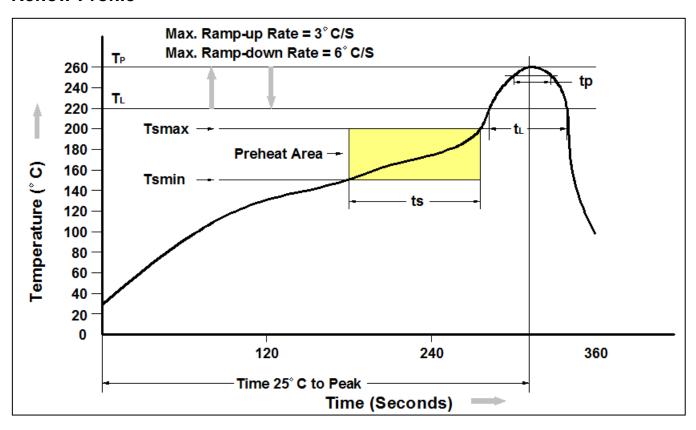
D : Production Code

## **Ordering Information**

Part Number	Description	Quantity
CTL1103NS	SOP-8 Tape and Reel	2500 pcs



#### **Reflow Profile**



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150°C
Temperature Max. (Tsmax)	200°C
Time (ts) from (Tsmin to Tsmax)	60-120 seconds
Ramp-up Rate (t∟ to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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